

Abstract

Device for testing electronic components

5 The invention is based on a device for testing electronic components (4) with
at least one test socket (1) with test contacts (2), with a nest (3), in which at
least one electronic component (4) can be placed, and with at least one
cleaning unit (6, 7; 8, 9; 10, 7, 9) for the test contacts (2) of the test
socket (1), wherein by means of a relative movement, which can be carried
10 out as a test stroke, between the test socket (1) and nest (3) the electronic
component (4) can be pressed against, and lifted from, the test contacts (2) of
the test socket (1). According to the invention the at least one cleaning
unit (6, 7; 8, 9; 10, 7, 9) is designed in such a manner that during each test
stroke the test contacts (2) come into contact with the at least one cleaning
15 unit (6, 7; 8, 9; 10, 7, 9).

Fig. 1